Message from the Chairs – MUTATION 2015

It is our pleasure to welcome you to the 10th edition of the International Workshop on Mutation Analysis (Mutation 2015), collocated with the 8th IEEE International Conference on Software Testing, Verification and Validation (ICST’15) in Graz, Austria. During its ten editions, the Mutation workshop has provided a forum to bring together researchers and practitioners, enabling them to exchange ideas, address fundamental challenges in mutation testing, and discuss new applications of mutation.

Mutation 2015 received 18 submissions and each paper was reviewed by at least three members of the program committee. After the reviewing and discussion process, the program committee accepted 10 papers (8 full papers, 1 short paper, and 1 industrial paper).

Mutation 2015 features a keynote given by Paul Ammann on how to transform mutation testing from the technology of the future into the technology of the present. Moreover, the three panelists Mark Harman, Jeff Offutt, and Yue Jia accepted our invitation to discuss what makes an effective mutation tool and how to bridge the gap between research and industry tools.

Finally, we would like to thank the program committee and the external reviewers for their contributions, and the authors and participants for assuring the quality and success of this workshop.

Enjoy the workshop!

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